

The Effect of Shape Deformation on Two-Dimensional Electrical Impedance Tomography

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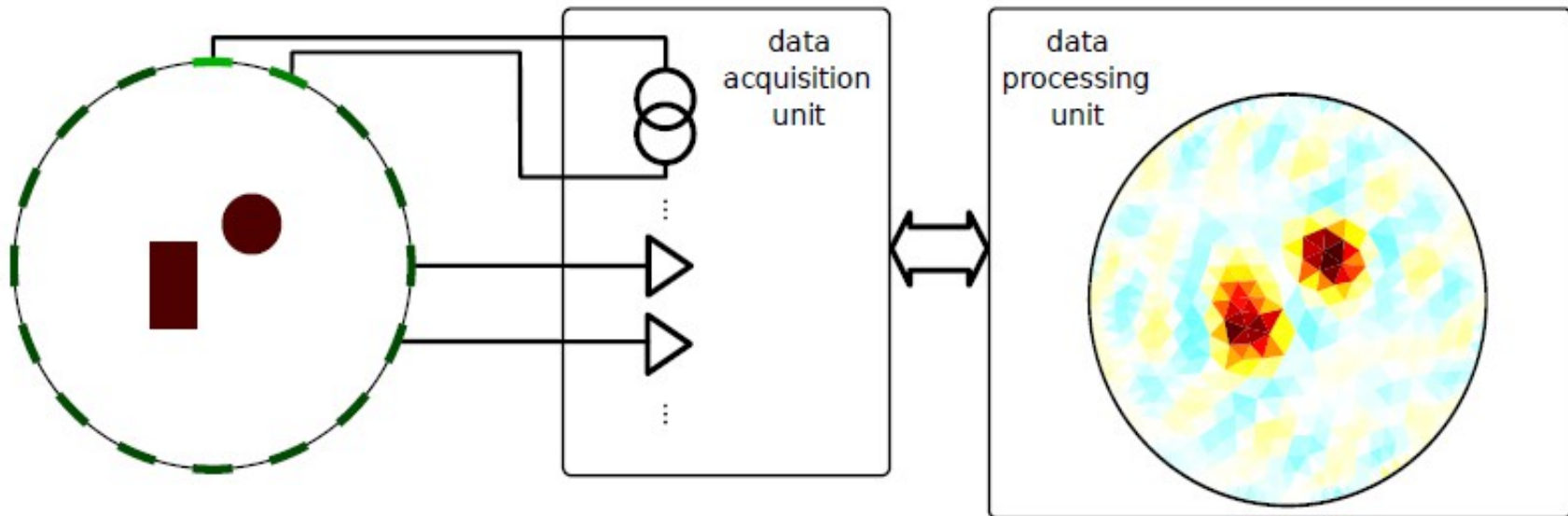


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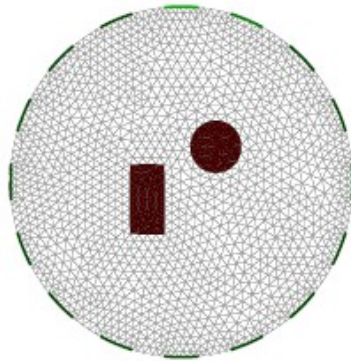
Electrical Impedance Tomography



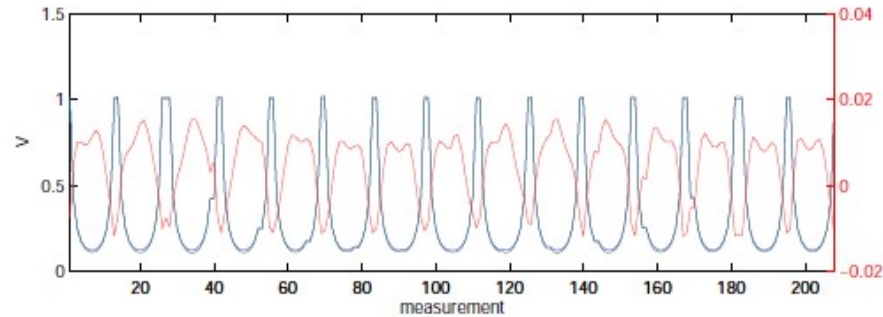
Electrical Impedance Tomography



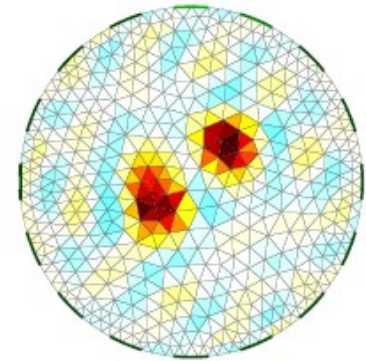
The Tools



(a) forward

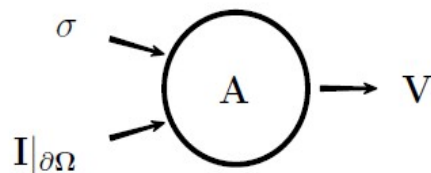


(b) voltage measurements



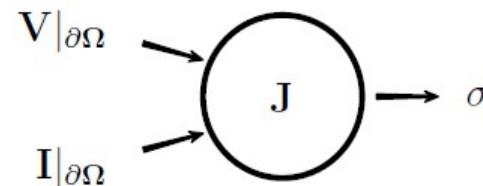
(c) inverse

- Finite Element Method



(a) forward

- Inverse Problem



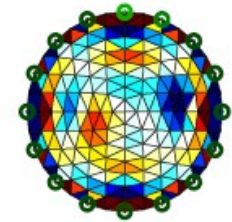
(b) inverse

Shape Deformations

- Using Difference EIT, most unknowns do not affect image quality as long as they are not changing:
 - e.g. contact impedance,
 - electrode location, or
 - electrode area[1]
- ... but what happens when the body *is* deforming?

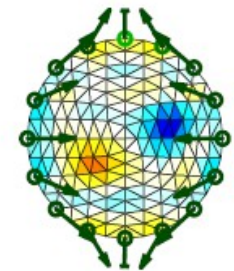
Shape Deformations

- Many shape deformations result in artifacts[2]



(b)

- Some deformations can be reconstructed if conductivity is isotropic[3]



(c)

- Conformal changes are interesting:
 - Isotropic conductivities remain isotropic under conformal deformations[4]

[2] A Adler et al, *Impedance imaging of lung ventilation: do we need to account for chest expansion?*, 1996, IEEE BME

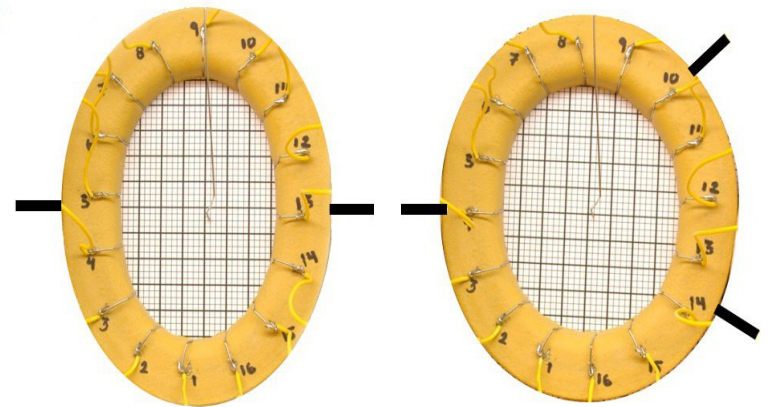
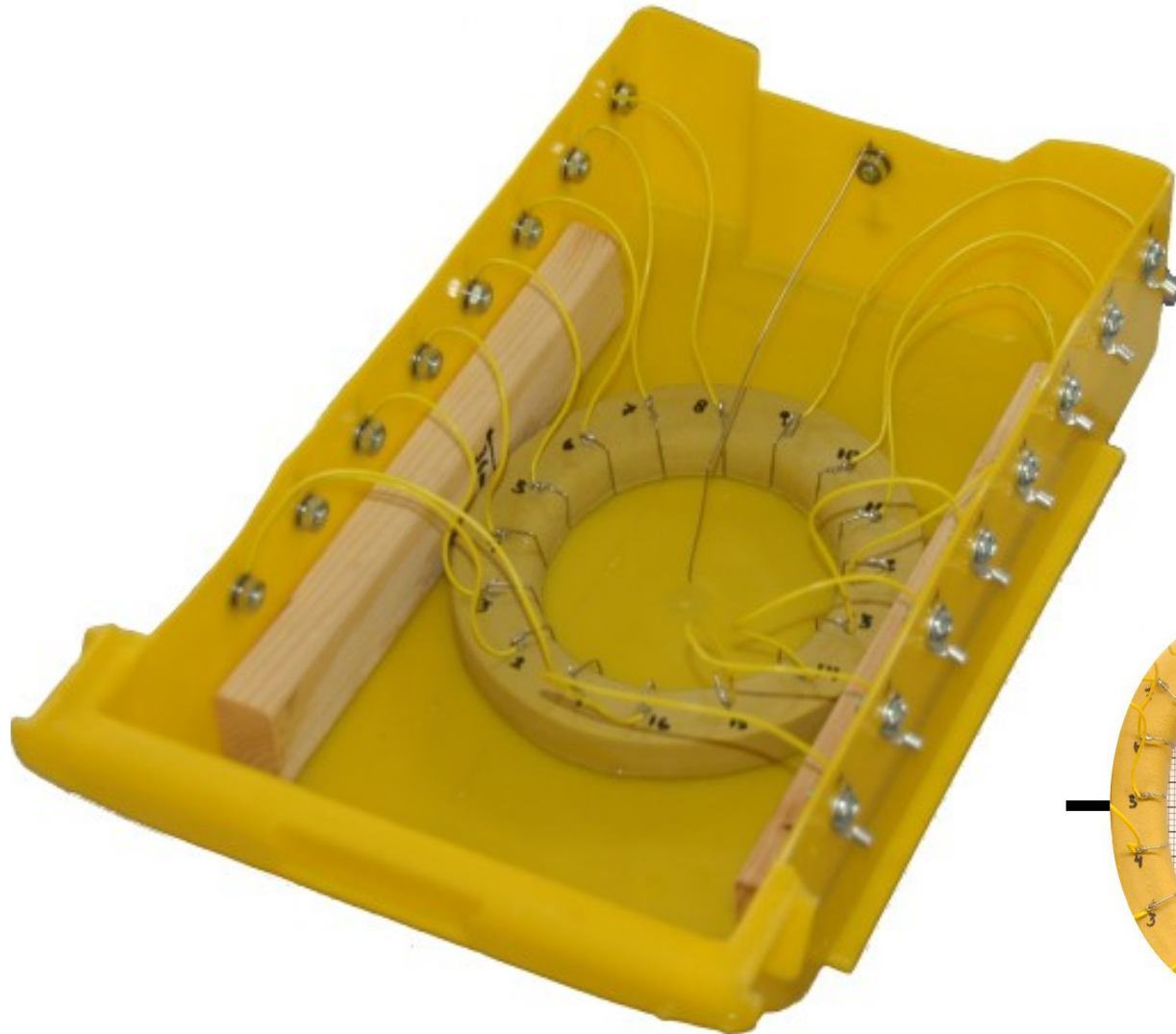
[3] M. Soleimani, et al., *Imaging of conductivity changes and electrode movement in EIT*, *Physiol. Meas.*, May 2006.

[4] WRB Lionheart, *Boundary Shape and Electrical Impedance Tomography*, 1998, IOP Journal Inv. Problems

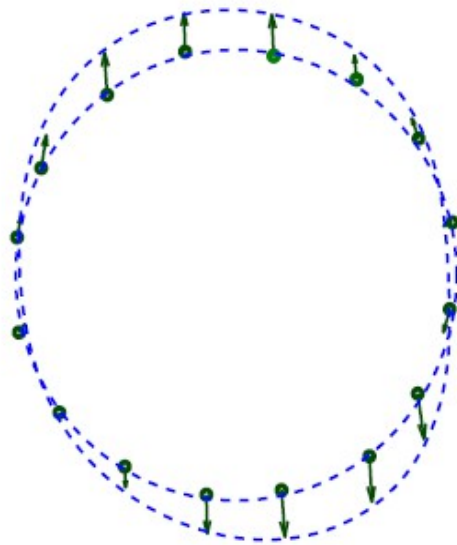
Contributions

- i. Phantom
- ii. Simulated Deformations
- iii. FEM Deformations
- iv. Conformal Motions
- v. Electrode Models

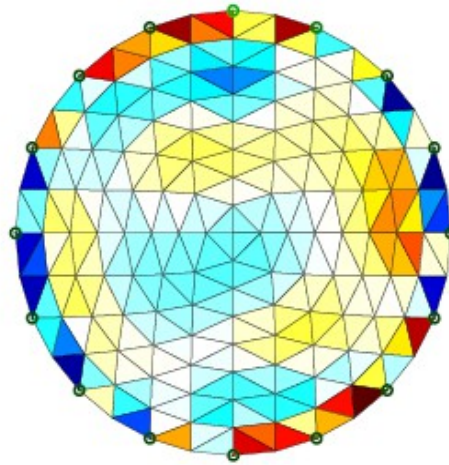
i. Phantom



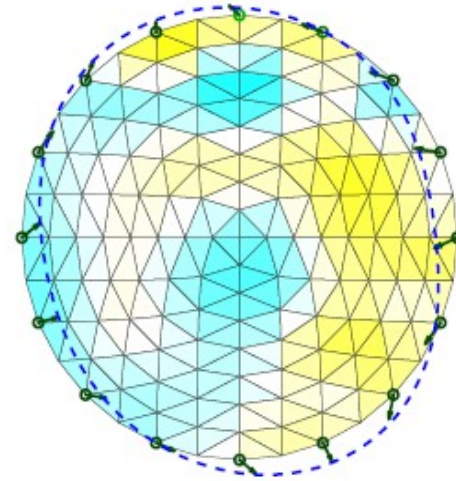
i. Phantom



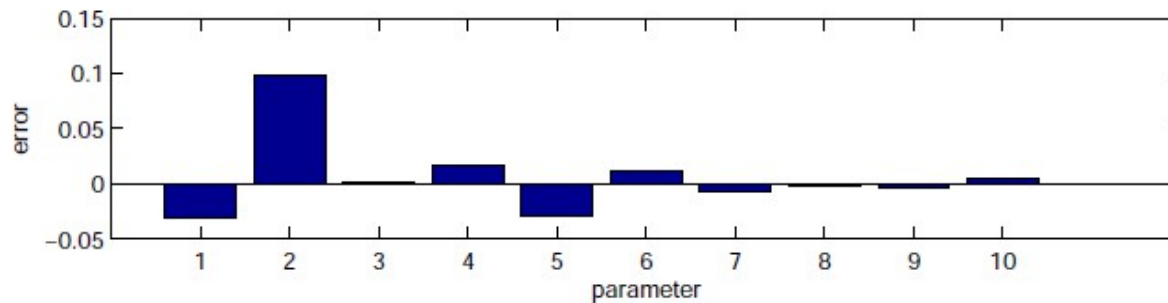
(a) true displacements



(b) naive reconstruction



(c) movement reconstruction



(d) parameter error

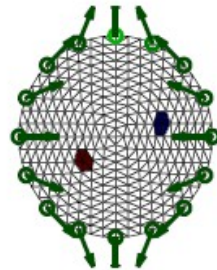
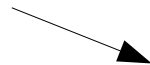
$$\theta' = \theta + \theta_k$$

$$r' = r \sum_{n=0}^N a_n \cos(n\theta') + b_n \sin(n\theta')$$

1: θ_k , 2: a_0 , 3,4: a_1, b_1 , 5,6: a_2, b_2 , 7,8: a_3, b_3 , 9,10: a_4, b_4

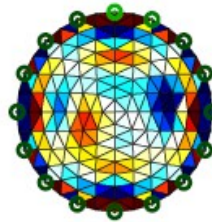
ii. Simulated Deformations

Forward Model



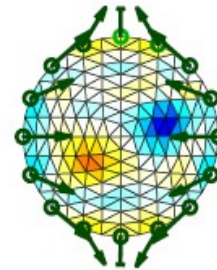
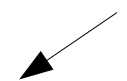
(a)

Naive



(b)

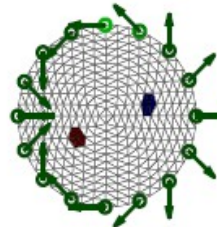
Reconstruction
(including Electrode Movement)



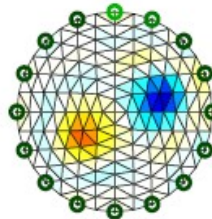
(c)

Non-Conformal

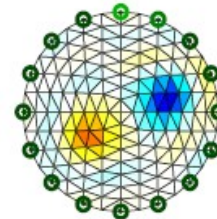
$$z \rightarrow 0.99x + i1.01y$$



(d)



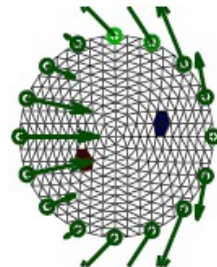
(e)



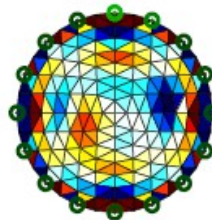
(f)

Conformal

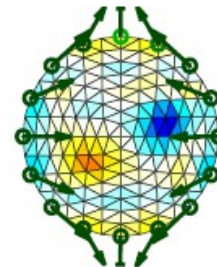
$$z \rightarrow z + 0.01z^2$$



(g)



(h)



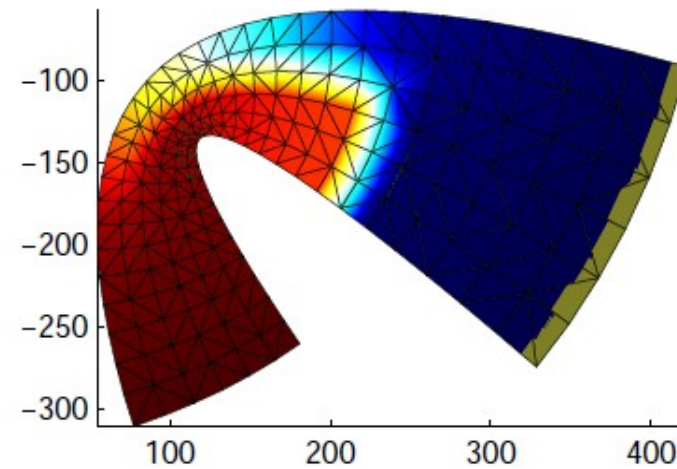
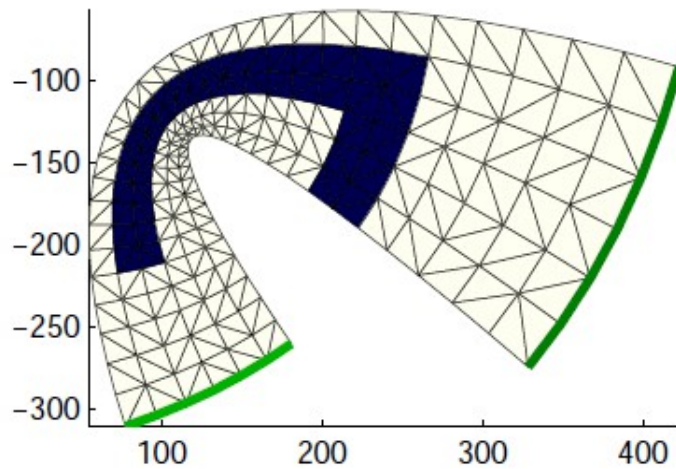
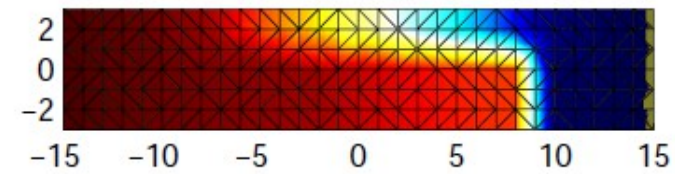
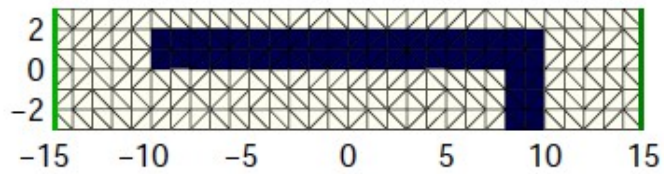
(i)

Combined

iii. FEM Deformations

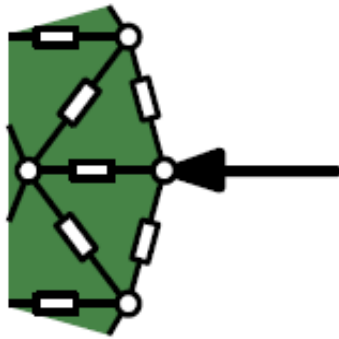
- If the EIT measurements don't change after a shape deformation, explains how conductivity must have changed
- If the conductivity is isotropic then, *iff* the shape change is conformal will the reconstructed conductivity be isotropic
- In the isotropic case, showed solution converges for a conformal shape change

iv. Conformal Motions

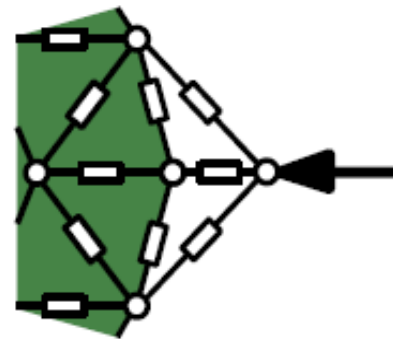


$$z \rightarrow \exp((z - 20 - i80)/100) \cdot (z + i20) \cdot (z - i10),$$

v. Electrode Models



Point Electrode Model

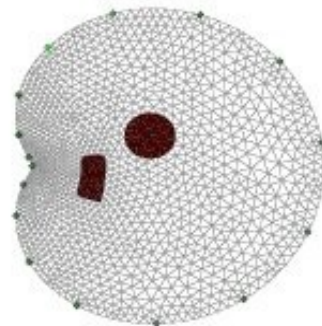


Complete Electrode Model

- With respect to conformal deformations:
 - PEM does not introduce artifacts.
 - What about CEM?

Summary

- Two-dimensional reconstructions can have undetected conformal deformations
 - It is not possible to reconstruct boundary deformation solely from voltages
- Measurement noise can be used to approximate electrode area & contact impedance errors



$$z = x + iy; z \rightarrow z + 0.4z^2$$

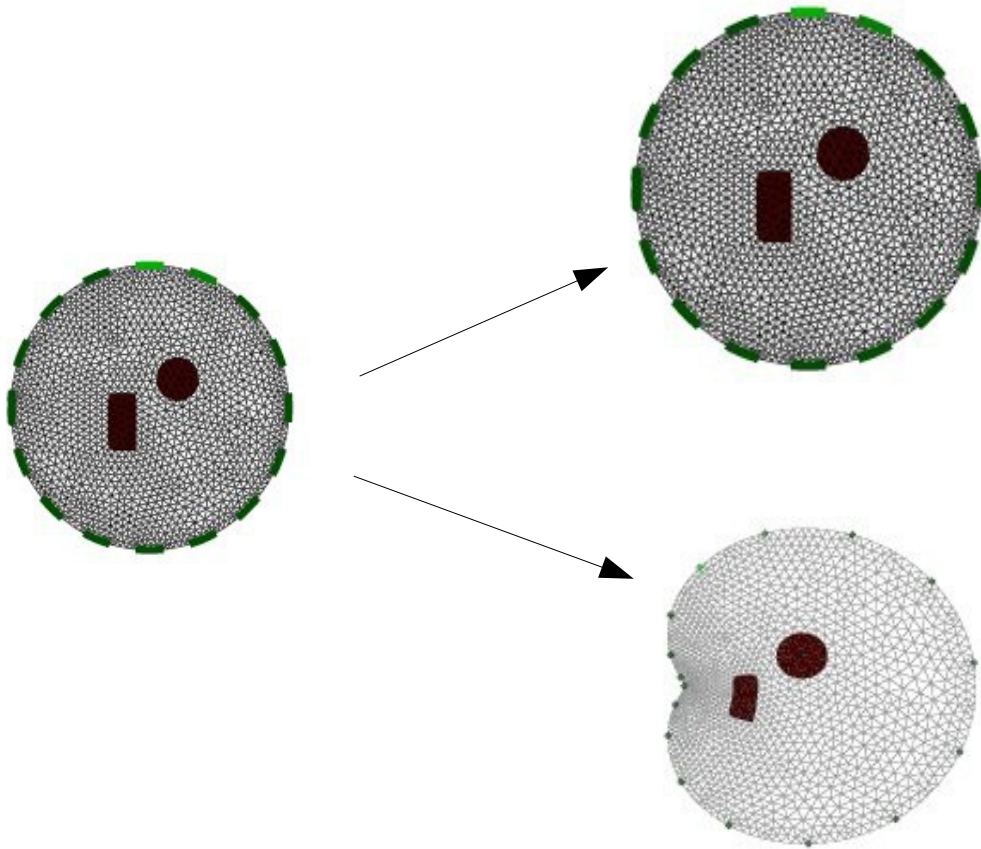
Future Work

- Deformation decomposition: Conformal/Non-Conformal
- Electrodes:
 - Simultaneous contact impedance reconstruction
 - Detect conformal changes when electrodes are of fixed size
- Extend this work to three-dimensions

Thank You

Questions?

v. Electrode Models



Dilation

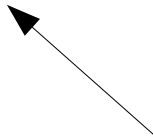
Complex

$$z = x + iy; z \rightarrow z + 0.4z^2$$

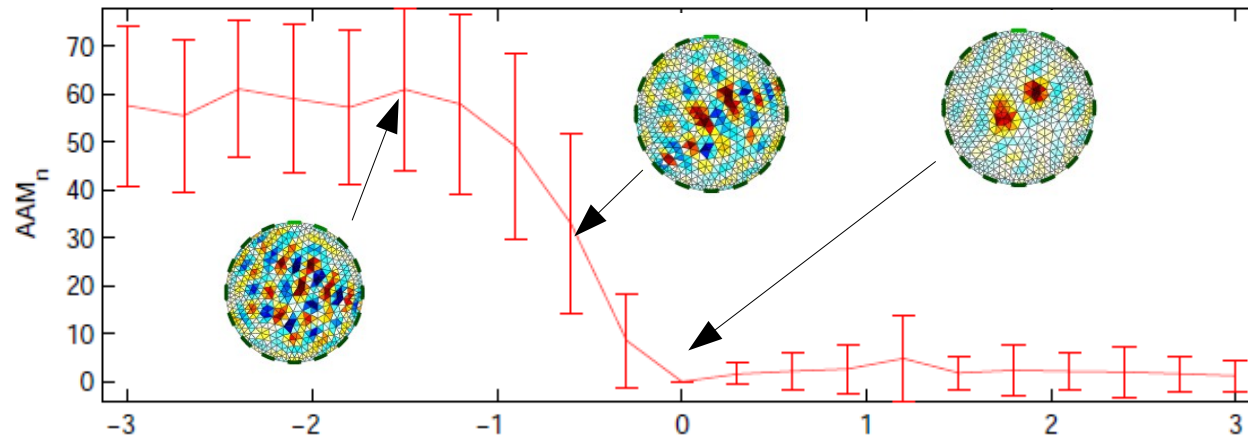
v. Electrode Models

Table 1 : Electrode Model Behaviour under Deformation

Model	Deformation		AAM _n	Comment
	Domain	Electrode		
PEM	dilation	matching	0	
	complex		0.0807	
	dilation	fixed	0	
CEM	dilation	matching	0.0010	
	complex		2.013	artifacts (deformed)
	dilation	fixed	5.5	artifacts (ringing)


$$\text{AAM}_n = \sum \left[\frac{c_1 - c_0}{c_0} \right]^2$$

v. Electrode Models



$$AAM_n = \sum \left[\frac{c_1 - c_0}{c_0} \right]^2$$

$$z_c = 10^{\mathcal{N}(\mu, \sigma^2)}$$

$$3 \leq \mu \leq 3$$

$$\sigma^2 = |\mu|$$